

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/526,686	CHARRIN ET AL.	
Examiner		Son T. Nguyen	Art Unit	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,382,418	05-2002	Weder, Donald E.	206/423
*	B	US-4,223,480	09-1980	Welty, Gary A.	47/73
*	C	US-4,216,622	08-1980	Hollenbach et al.	47/71
*	D	US-4,057,932	11-1977	Spencer, Henry Anderson	47/77
*	E	US-4,186,670	02-1980	Hagner, Mats	111/200
*	F	US-3,195,272	07-1965	MOSHER EDWARD G; et. al.	47/73
*	G	US-6,050,027	04-2000	Pavelka et al.	47/84
H	US-				
I	US-				
J	US-				
K	US-				
L	US-				
M	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N		JP 2000041489 A	02-2000	Japan	TANAKA, MINORU	
O		DE 4244399 A1	07-1994	Germany	GARREL et al.	
P		FR 2841114 A1	12-2003	France	PICORY et al.	
Q		JP 01058651 A	03-1989	Japan	KOBAYASHI, MASATO	
R						
S						
T						

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.